Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/525,410	FENG ET AL.
Examiner	Art Unit

1626

Karen	Cheng	

SEARCHED				
Class	Subclass	Date	Examiner	
548	311.1	1/4/2007	кс	
548	315.4	1/4/2007	кс	
548	347.1	1/4/2007	кс	
548	355.1	1/4/2007	кс	
549	429	1/4/2007	кс	
549	460	1/4/2007	KC	
514	397	2/28/2007	кс	
548	311.7	2/28/2007	кс	
514	383	2/28/2007	кс	
514	422	2/28/2007	КС	
548	266.4	2/28/2007	кс	
548	526	2/28/2007	кс	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
514	311.7	2/28/2007	КС	
514	383	2/28/2007	кс	
514	422	2/28/2007	кс	
548/ 311.7,	266.4, 526	2/28/2007	кс	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
STN Structure Search (see attached)	1/4/2007	кс	
EAST Search (see attached)	1/4/2007	кс	
Inventor Name Search	1/4/2007	кс	
STN Structure Search (updated, see attached)	2/28/2007	кс	
EAST Search (see attached)	2/28/2007	кс	
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